

#### CMT802XNX High-Speed, Dual-Channel Digital Isolator

#### 1 Features

- Safety-related certifications
  - DIN VDE V 0884-11: 2017-01
  - UL 1577 component recognition program
  - CSA certification according to IEC 60950-1, IEC 62368-1, IEC 61010-1 and IEC 60601-1 end equipment standards
  - CQC approval per GB4943.1-2022
  - TUV certification according to EN 60950-1, EN 62368-1 and EN 61010-1
- Robust electromagnetic compatibility
  - System-level ESD, EFT, and surge immunity
  - ±8 kV IEC 61000-4-2 contact discharge protection across isolation barrier
  - Low emissions
- Data rate: up to 10 Mbps
- Wide supply range: 2.5 to 5.5 V
- Operation temperature: -40°C to 125°C
- Robust isolation barrier
  - More than 40-year projected lifetime
  - Up to 3.75 kV<sub>RMS</sub> isolation rating
  - Up to 5.3 kV surge capability
  - ±200 kV/µs typical CMTI
- Default output high or low options
- Low power consumption, typical 1.5 mA per channel at 1 Mbps
- Low propagation delay: 9 ns typical (5V supplies)
- SOIC 8 package (narrow body)

### 2 Applications

- Industrial automatic control
- New energy vehicles
- Solar inverters
- Motor controlIsolated SPI
- General purpose multichannel isolation

### 3 Description

The CMT802XNX series devices are high-performance, dual channel digital isolators with as high as  $3.75~kV_{ms}$  isolation voltage by means of silicon-dioxide (SiO2) insulation barrier.

The digital isolator is used to communicate between two different power supply domains while prevents noise currents on a data bus or other circuits from entering the local ground and interfering with or damaging sensitive circuitry.

This device comes with enable pins that can be used to put the respective outputs in high impedance for multi-master driving applications and to reduce power consumption. The CMT802XNX device has four forward and up to two reverse-direction channels. If the input power or signal is lost, the default output is high for the CMT802XNH device and low for the CMT802XNL device. See the Device Functional Modes section for further details.

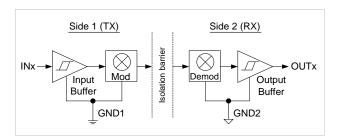
The isolator provides high electromagnetic immunity and low emissions at low-power consumption. Through innovative chip design and layout techniques, electromagnetic compatibility of the CMT802XNX device has been significantly enhanced to ease system-level ESD, EFT, surge, and emissions compliance.

The CMT802XNX series device is available in narrow-body (NB) 8-pin SOIC package.

#### **Device Information**

Part No.	Package	Body Size (mm x mm)				
CMT802XNX	NB(N) SOIC-8	5.0 x 3.9				
Refer to section 14 for ordering information.						

#### Simplified Schematic



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## 4 Absolute Maximum Ratings

Table 1. Absolute Maximum Ratings[1]

Parameters	Symbol	Condition	Min.	Max.	Unit
Power supply voltage <sup>[2]</sup>	VDD1, VDD2		-0.5	6.5	V
Maximum input voltage	INx	x = A, B	-0.4	VDD+0.4	V
Maximum output voltage	OUTx	x = A, B	-0.4	VDD+0.4	V
Maximum Input / output pulse voltage	-	Pulse width should be less than 100 ns, and the duty cycle should be less than 10%	-0.8	VDD+0.8	V
Common-mode transient immunity	CMTI			±200	kV/us
Output current	Io		-15	15	mA
Maximum surge immunity	-			5.3	kV
Operating temperature	T <sub>A</sub>		-40	125	$^{\circ}$
Storage temperature	$T_{STG}$		-40	150	$^{\circ}$

#### Notes:

- [1]. Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.
- [2]. All voltage values except differential I/O bus voltages are with respect to the local ground terminal (GND1 or GND2) and are peak voltage values.

## 5 Recommended Operating Conditions

**Table 2. Recommended Operating Conditions** 

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Power supply voltage	VDD1, VDD2		2.5	5	5.5	V
High level input voltage	V <sub>IH</sub>	VDDI: input side VDD	0.7*VDD		VDDI	V
Low level input voltage	$V_{IL}$	VDDI: input side VDD	0		0.3VDD	٧
Data rate	DR		0		5	Mbps
Operating temperature	T <sub>A</sub>		-40	25	125	$\mathbb{C}$
Junction temperature	TJ		-40		150	$\mathbb{C}$

## 6 ESD Ratings

Table 3. ESD Ratings

Parameter	Symbol	Condition	Max.	Unit
Floring static disable and	V	Human-body model (HBM)	±8000	
Electrostatic discharge V <sub>ESD</sub>		Charged-device model (CDM)	± 2000	V

#### Notes:

- 1. IEC ESD strike is applied across the barrier with all pins on each side tied together creating a two-terminal device.
- 2. Testing is carried out in air or oil to determine the intrinsic contact discharge capability of the device.



**Caution!** ESD sensitive device. Precaution should be used when handling the device in order to prevent performance degradation or loss of functionality.

## 7 Pin Description

The series part number CMT802ANX, CMT802BNX and CMT802CNX are available for narrow-body (N) 8-pin SOIC package. The pin lists are shown as below.

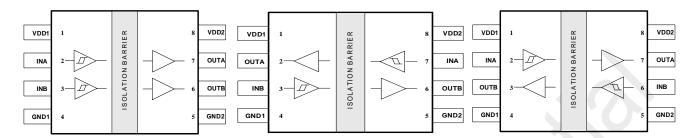


Figure 1. CMT802ANX Pin List

Figure 2. CMT802BNX Pin List

Figure 3. CMT802CNX Pin List

Table 4. CMT802A / 2B / 2CNX Pin Description

	Pin Nmuber				
Pin Name	NB SOIC-8			I/O	Description
	CMT802AN	CMT802BN	CMT802CN	1/0	Description
GND1	4	4	4		Left ground
GND2	5	5	5		Right ground
INA	2	7	2	I	Input, channel A
INB	3	3	6	I	Input, channel B
NC	-	-	-	-	Disconnect / connect to the GND
OUTA	7	2	7	0	Output, channel A
OUTB	6	6	3	0	Output, channel B
VDD1	1	1	1	-	Power supply for left side
V <sub>DD2</sub>	8	8	8	-	Power supply for right side

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### 8 Typical Application

### 8.1 Typical Application Schematic

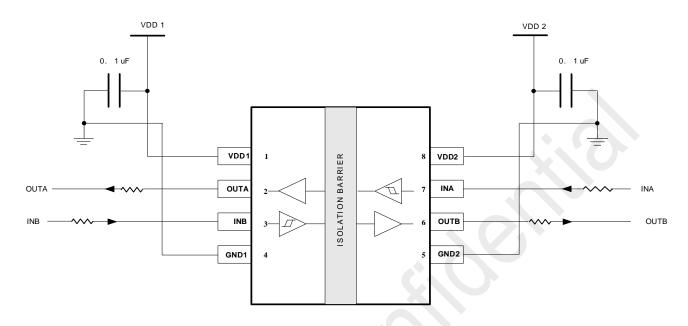


Figure 4. Typical Application Schematic (Take the CMT802BNX as an example)

Note: users should be careful not to connect ground and VDD reversely

### 8.2 PCB Layout Guidelines

The CMT802XNX requires a 0.1  $\mu$ F bypass capacitor in both input side and output side. The capacitor should be placed as close as possible to the package pin of VDD1 and VDD2 respectively. The figures below show the recommended PCB layout. Please make sure the space under the chip keeps free from planes, traces, pads and via. To enhance the robustness of design, users may also include resistors (50  $\sim$  300  $\Omega$ ) in series with the inputs and outputs if the system is excessively noisy. The series resistors also improve the system reliability such as latch-up immunity.

The typical output impedance of an isolator driver channel is approximately 50  $\Omega$  ± 40%. When driving loads where transmission line effects will be a factor, output pins should be appropriately terminated with controlled impedance PCB traces.

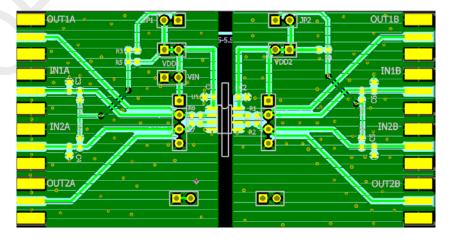


Figure 5. Recommended PCB Layout

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## 9 Parameter Measurement Circuit Setup

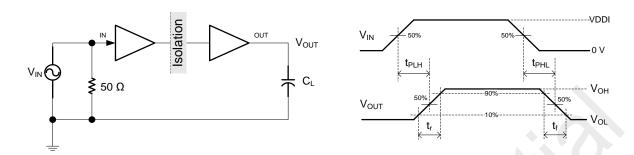


Figure 6. Switching Characteristics Test Circuit and Voltage Waveforms

#### Notes:

- 1. The input pulse is supplied by a generator  $V_{IN}$  having the following characteristics:  $f_{PULSE} \le 100$  kHz, 50% duty cycle,  $t_r \le 3$  ns,  $t_f \le 3$
- 2. Load capacitance influences the measurement results quite a lot, including instrumentation and fixture capacitance, totally no more than 15 pF loading is preferred.

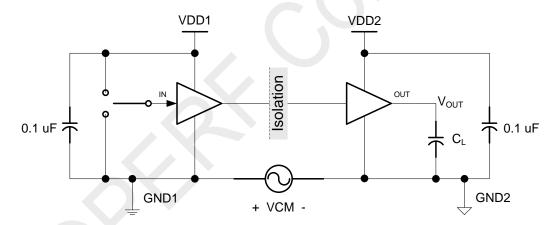


Figure 7. Common-Mode Transient Immunity Test Circuit

#### Notes:

1. CL = 15 pF, the total instrumentation and connection is within ±20%.

## 10 Electrical Specifications

#### 10.1 Electrical Characteristics

VDD1 =2.5V~5.5V, VDD2= 3.0V~5.5V, TA= -40 to 125  $^{\circ}$ C. Unless otherwise noted, typical values are at VDD1=5V, VDD2=5V, TA=25  $^{\circ}$ C.

**Table 5. Electrical Characteristics** 

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Dower on react	$V_{POR}$	POR threshold as during power- up		2.3		V
Power on reset	V <sub>HYS</sub>	POR threshold hysteresis		0.1		V
	V <sub>IT</sub>	Input threshold at rising edge			0.7*VDD1	٧
Input threshold	V <sub>IT-</sub>	Input threshold at falling edge	0.3*VDD1			V
	V <sub>ITHYS</sub>	Input threshold hysteresis		0.2*VDD1		V
High level output voltage	V <sub>OH</sub>	I <sub>OH</sub> = -4mA	VDD- 0.3			V
Low level output voltage	V <sub>OL</sub>	I <sub>OL</sub> = 4mA			0.3	V
Output impedance	R <sub>o</sub>			50		Ω
Input pull high or low current	lpull			10	15	uA
Start-up time after POR	trbs			10		us
Common mode transient	CMTI			200		kV/us

### 10.2 Supply Current Characteristics with 5 V Supply

VDD1 = VDD2 = 5V,  $T_A$ = -40 to 125 °C.

Table 6. Supply Current Characteristics with 5 V Supply

Parameter	Symbol	Тур.	Max.	Unit
CMT802ANX				
Supply current	I <sub>DD1</sub>	0.67		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	1.14		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.96		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	1.19		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.82		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	1.34		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.85		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	2.84		mA
CMT802BNX				
Supply current	I <sub>DD1</sub>	1.12		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	1.14		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.27		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	2.30		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.79		mA

Parameter	Symbol	Тур.	Max.	Unit
All channels switching with 1 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD2</sub>	1.83		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	2.21		mA
All channels switching with 10 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD2</sub>	2.25		mA
CMT802CNX				
Supply current	I <sub>DD1</sub>	1.13		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	1.13		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.35		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	2.30		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.83		mA
All channels switching with 1 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD2</sub>	1.82		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	2.25		mA
All channels switching with 10 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD2</sub>	2.24		mA

Table 7. Supply Current with 5 V Supply- Characteristics of CMT802XNX

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Data rate	DR		0	,	5	Mbps
Minimum pulse width	PW	See figure 6, CL = 15 pF		5	5	ns
Propagation delay rising	t <sub>PLH</sub>	See figure 6, CL = 15 pF		9	15	ns
Propagation delay falling	t <sub>PHL</sub>	See figure 6, C <sub>L</sub> = 15 pF		9	15	ns
Pulse width distortion	PWD	See figure 6, CL = 15 pF			5	ns
Rising time	tr	See figure 6, C <sub>L</sub> = 15 pF			5	ns
Falling time	tf	See figure 6, CL = 15 pF			5	ns
Peak eye diagram Jitter	t <sub>JIT</sub> (PK)			400		ps
Channel-to-channel delay Skew	t <sub>SK</sub> (c2c)			1.5	2.5	ns
Part-to-part delay skew	t <sub>SK</sub> (p2p)				5	ns

## 10.3 Supply Current Characteristics with 3.3 V Supply

VDD1 = VDD2 = 3.3V,  $T_A = -40$  to 125 °C.

Table 8. Supply Current Characteristics with 3.3 V Supply

Parameter	Symbol	Тур.	Max.	Unit
CMT802ANX				
Supply current	I <sub>DD1</sub>	0.67		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	1.14		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.94		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	1.18		mA

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Parameter	Symbol	Тур.	Max.	Unit
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.80		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	1.27		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.83		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	2.26		mA
CMT802BNX				
Supply current	$I_{DD1}$	1.12		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	1.13		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.25		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	2.29		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.71		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 pF$	I <sub>DD2</sub>	1.75		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	2.01		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	2.05		mA
CMT802CNX				
Supply current	I <sub>DD1</sub>	1.14		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	1.14		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.33		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	2.31		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.75		mA
All channels switching with 1 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD2</sub>	1.74		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	2.04		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	2.03		mA

Table 9. Supply Current with 3.3 V Supply - Characteristics of CMT802XNX

Table 3. Supply Suffere with 3.5 v Supply - Sharacteristics of Switted 2007							
Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit	
Data rate	DR		0		5	Mbps	
Minimum pulse width	PW	See figure 9, C <sub>L</sub> = 15 pF		5		ns	
Propagation delay rising	t <sub>PLH</sub>	See figure 9, C <sub>L</sub> = 15 pF		9	15	ns	
Propagation delay falling	t <sub>PHL</sub>	See figure 9, CL = 15 pF		9	15	ns	
Pulse width distortion	PWD	See figure 9, CL = 15 pF			5	ns	
Rising time	tr	See figure 9, CL = 15 pF			5	ns	
Falling time	tf	See figure 9, C <sub>L</sub> = 15 pF			5	ns	
Peak eye diagram Jitter	t <sub>JIT</sub> (PK)			400		ps	
Channel-to-channel Delay Skew	t <sub>SK</sub> (c2c)			1.5	2.5	ns	
Part-to-part delay skew	t <sub>SK</sub> (p2p)				5	ns	

### 10.4 Supply Current Characteristics with 2.5 V Supply

VDD1 = VDD2 = 2.5 V,  $T_A$ = -40 to 125 °C.

Table 10. Supply Current Characteristics with 2.5 V Supply

Parameter	Symbol	Тур.	Max.	Unit
CMT802ANX				
Supply current	I <sub>DD1</sub>	0.66		mA
$EN = VDDI, V_{IN} = 0 V$	I <sub>DD2</sub>	1.13		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.93		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	1.18		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.79		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	1.24	<b>\</b>	mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.82		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	2.00		mA
CMT802BNX	-			
Supply current	I <sub>DD1</sub>	1.11		mA
EN = VDDI,V <sub>IN</sub> =0 V	I <sub>DD2</sub>	1.13		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.24		mA
$EN = VDDI, V_{IN} = VDDI,$	I <sub>DD2</sub>	2.28		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.65		mA
All channels switching with 1 Mbps square wave input, C <sub>L</sub> = 15 pF	I <sub>DD2</sub>	1.69		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.86		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	1.90		mA
CMT802CNX				1
Supply current	I <sub>DD1</sub>	1.14		mA
EN = VDDI,V <sub>IN</sub> =0 V	I <sub>DD2</sub>	1.13		mA
Supply current: device is disabled.	I <sub>DD1</sub>	2.32		mA
EN = VDDI,V <sub>IN</sub> =VDDI,	I <sub>DD2</sub>	2.30		mA
Supply current: 1 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.74		mA
All channels switching with 1 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	1.72		mA
Supply current: 10 Mbps square wave clock input AC signal.	I <sub>DD1</sub>	1.94		mA
All channels switching with 10 Mbps square wave input, $C_L = 15 \text{ pF}$	I <sub>DD2</sub>	1.92		mA

Table 11. Supply Current with 2.5 V Supply - Characteristics of CMT802XNX

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Data rate	DR		0		5	Mbps
Minimum pulse width	PW	See figure 9, CL = 15 pF		5	5	ns
Propagation delay rising	t <sub>PLH</sub>	See figure 9, CL = 15 pF		9	15	ns
Propagation delay falling	t <sub>PHL</sub>	See figure 9, C <sub>L</sub> = 15 pF		9	15	ns
Pulse width distortion	PWD	See figure 9, C <sub>L</sub> = 15 pF			5	ns
Rising time	tr	See figure 9, C <sub>L</sub> = 15 pF			5	ns

Parameters	Symbol	Condition	Min.	Тур.	Max.	Unit
Falling time	tf	See figure 9, C <sub>L</sub> = 15 pF			5	ns
Peak eye diagram Jitter	t <sub>JIT</sub> (PK)			400		ps
Channel-to-channel	t <sub>SK</sub> (c2c)			1.5	2.5	ns
Delay Skew	i <sub>SK</sub> (626)					115
Part-to-part delay skew	t <sub>SK</sub> (p2p)				5	ns

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### 10.5 Typical Characteristics

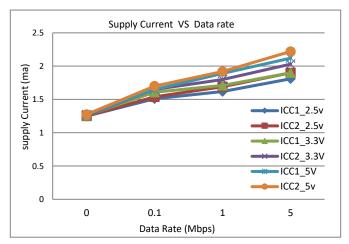


Figure 8. Supply Current vs. Data Rate (with 15-pF Load) T<sub>A</sub>=25°C C<sub>L</sub>=15pF

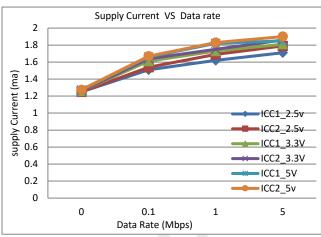


Figure 9. Supply Current vs. Data Rate (with No Load) T<sub>A</sub>=25°C C<sub>L</sub>=No Load

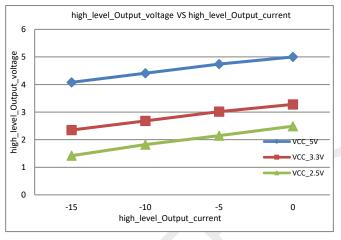


Figure 10. High-Level Output Voltage vs. High-Level Output Current (T<sub>A</sub>=25°C)

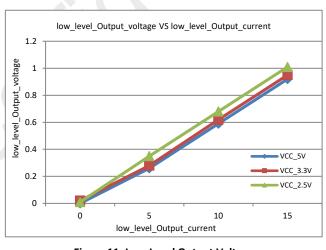


Figure 11. Low-Level Output Voltage vs. Low-Level Output Current(T<sub>A</sub>=25°C)

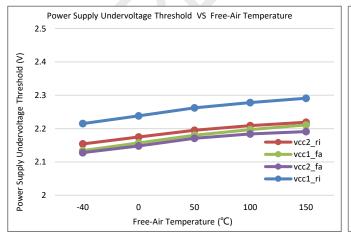


Figure 12. Power Supply Under-voltage Threshold vs. Free-Air Temperature

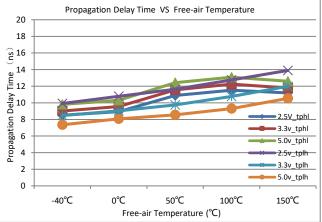


Figure 13. Propagation Delay Time vs. Free-Air Temperature

### 10.6 Insulation Specifications

**Table 12. Insulation Specifications** 

Parameters	Sym.	Condition	Value	Unit
			NB SOIC-8	
External clearance <sup>[1]</sup>	CLR	The shortest terminal-to-terminal distance through air	4.0	mm
External creepage <sup>[1]</sup>	CRP	The shortest terminal-to-terminal distance across the package surface	4.0	mm
Distance through insulation	DTI	Minimum internal gap	20	um
Comparative tracking index	CTI	DIN EN 60112 (VDE 0303-11);IEC 60112	> 400	V
Material group	-		II	-
		Rated mains voltage ≤ 300 V <sub>RMS</sub>	1	-
Overvoltage category per IEC 60664-1	-	Rated mains voltage ≤ 600 V <sub>RMS</sub>	I-IV	-
		Rated mains voltage ≤ 1000 V <sub>RMS</sub>	1-111	-
DIN VDE V 0884-11:2017-01 <sup>[2]</sup>				
Maximum repetitive isolation voltage	V <sub>IORM</sub>		565	$V_{pk}$
Maximum isolation working voltage	Vioun	AC voltage (sine wave); Time dependent dielectric breakdown (TDDB) test	400	V <sub>RMS</sub>
Waximum isolation working voltage	VIOWW	DC voltage	565	$V_{DC}$
Maximum transient isolation voltage	V <sub>IOTM</sub>	V <sub>TEST</sub> = V <sub>IOTM</sub> ,t = 60 s (qualification); t = 1 s (100% production)	5300	$V_{pk}$
Maximum surge isolation voltage <sup>[3]</sup>	V <sub>IOSM</sub>	Test method per IEC60065, 1.2/50 us waveform, V <sub>TEST</sub> = 1.6 x V <sub>IOSM</sub> (qualification)	5384	$V_{pk}$
		Method a: After I/O safety test subgroup 2/3, $V_{ini}$ = $V_{IOTM}$ , $t_{ini}$ = 60 s; $V_{pd(m)}$ = 1.2 × $V_{IORM}$ , $t_m$ = 10 s	≤5	
Apparent charge <sup>[4]</sup>	$q_{pd}$	Method a: After environmental tests subgroup 1, $V_{ini} = V_{IOTM}$ , $t_{ini} = 60 \text{ s}$ ; $V_{pd(m)} = 1.6 \times V_{IORM}$ , $t_m = 10 \text{ s}$	≤5	≤5pC
		Method b1: At routine test (100% production) and preconditioning (type test) $V_{ini} = V_{IOTM},  t_{ini} = 1  s;$ $V_{pd(m)} = 1.875 \times V_{IORM},  t_m = 1  s$	≤5	
Isolation capacitance, input to output <sup>[5]</sup>	C <sub>IO</sub>	V <sub>IO</sub> = 0.4 x sin (2πft), f = 1 MHz	0.6	pF
Isolation resistance, input to output <sup>[5]</sup>	R <sub>IO</sub>	V <sub>IO</sub> = 500 V	>10 <sup>10</sup>	Ω
Withstand isolation voltage	V <sub>ISO</sub>	$V_{TEST} = V_{ISO}$ , $t = 60$ s (qualification); $V_{TEST} = 1.2 \times V_{ISO}$ , $t = 1$ s (100% production)	3750	V <sub>RMS</sub>

#### Notes:

- [1]. Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed-circuit board do not reduce this distance. Creepage and clearance on a printed-circuit board become equal in certain cases. Techniques such as inserting grooves and/or ribs on a printed-circuit board are used to help increase these specifications.
- [2]. This coupler is suitable for safe electrical insulation only within the safety ratings. Compliance with the safety ratings shall be ensured by means of suitable protective circuits.
- [3]. Testing is carried out in air or oil to determine the intrinsic surge immunity of the isolation barrier.
- [4]. Apparent charge is electrical discharge caused by a partial discharge (pd).
- [5]. All pins on each side of the barrier are tied together creating a two-terminal device.

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### 10.7 Safety-related Certifications

**Table 13. Safety-related Certifications** 

VDE	UL		CQC	TUV
DIN VDE V0884-11:2017-01 ( Patents pending )	UL 1577 Component Recognition Program	Approved under CSA Component Acceptance Notice 5A	GB 4943.1-2011	EN 61010-1:2010 (3rd Ed) and EN 60950-1:2006/A2: 2013 ( Patents pending )
Certificate number: pending	Certificate number: UL-US-2439077-1	Certificate number: UL-CA-2429797-0	Certificate number: CQC23001382478	Client ID number: pending

### 10.8 Safety Limiting Values

Safety limiting intends to minimize potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the I/O can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures

**Table 14. Safety Limiting Values** 

	Symbol Test Condition		Value	
Parameters Parameters Parameters			NB SOIC-8	Unit
		$R_{\theta JA} = 140 \text{ °C/W}, V_1 = 5.5 \text{ V},$ $T_J = 125 \text{ °C}, T_A = 25 \text{ °C}$	160	mA
Safety input, output, or supply current	Is	$R_{\theta JA} = 84 \text{ °C/W}, V_1 = 5.5 \text{ V},$ $T_J = 125 \text{ °C}, T_A = 25 \text{ °C}$		mA
Total power dissipation at 25°C	Ps			W
Case temperature	Ts		125	$^{\circ}$

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### 10.9 Thermal Information

**Table 15. Thermal Information** 

Parameter	Symbol	Value NB SOIC-8	Unit
Junction-to-ambient thermal resistance	$\theta_{JA}$	78.9	°C/W
Junction-to-case (top) thermal resistance	θ <sub>JC</sub> (top)	41.1	°C/W
Junction-to-board thermal resistance	$\theta_{JB}$	49.5	°C/W

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### 11 Function Description

#### 11.1 Function Overview

The CMT802XNX device is a high-performance, quad-channel digital isolator with 3750 V<sub>RMS</sub> isolation rating. The CMT802XNX has an On-Off keying (OOK) modulation scheme to transmit the digital data across a silicon dioxide based isolation barrier. The transmitter sends a high-frequency carrier across the barrier to represent one digital state and sends no signal to represent the other digital state. The receiver demodulates the signal after advanced signal conditioning and produces the output through a buffer stage. If the ENx pin is low then the output goes to high impedance. The CMT802XNX also incorporates advanced circuit techniques to maximize the CMTI performance and minimize the radiated emissions due to the high frequency carrier and IO buffer switching. The figure below shows a conceptual detail of how the On-Off keying scheme works.

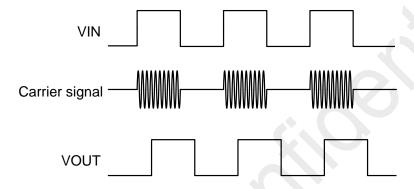


Figure 14. On-Off Keying Based Modulation Scheme

#### 11.2 Functional Modes

The table below lists the functional modes of the CMT802XNX.

	Table 10.1 among 1 and								
V <sub>DD1</sub>	V <sub>DD2</sub>	Input (INx) <sup>[2]</sup>	Output (OUTx)	Comment					
		Н	Н						
PU	PU	L	L	Normal operation: A channel output assumes the logic state of its input					
FU FU		Open	Default	Default mode: when INx is open, the corresponding channel output goes to its default logic state					
PD	PU	X	Default	Default mode: when VDDI is unpowered, a channel output assumes the logic state based on the selected default option.  When VDD1 transitions from unpowered to powered-up, a channel output assumes the logic state of the input.  When VDD1 transitions from powered-up to unpowered, channel output assumes the selected default state					
Х	PD	Х	Undetermined	When VDD2 is unpowered, a channel output is undetermined <sup>[3]</sup> . When VDD2 transitions from unpowered to powered-up, a channel output assumes the logic state of the input					

Table 16. Function Table<sup>[1]</sup>

#### 11.3 Insulation Lifetime

Insulation lifetime projection data is collected by using industry-standard Time Dependent Dielectric Breakdown (TDDB) test method. In this test, all pins on each side of the barrier are tied together creating a two-terminal device and high voltage applied between the two sides; See the figure below for TDDB test setup. The insulation breakdown data is collected at various high

voltages switching at 60 Hz over temperature. For reinforced insulation, VDE standard requires the use of TDDB projection line with failure rate of less than 1 part per million (ppm). Even though the expected minimum insulation lifetime is 20 years at the specified working isolation voltage, VDE reinforced certification requires additional safety margin of 20% for working voltage and 87.5% for lifetime which translates into minimum required insulation lifetime of 37.5 years at a working voltage that's 20% higher than the specified value.

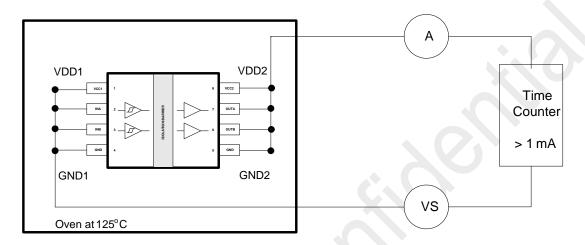


Figure 15. Test Setup for Insulation Lifetime Measurement

# 12 Packaging Information

The packaging information of the CMT802XNX is shown in the figures below.

### 12.1 CMT802XNX Narrow Body SOIC-8 Packaging

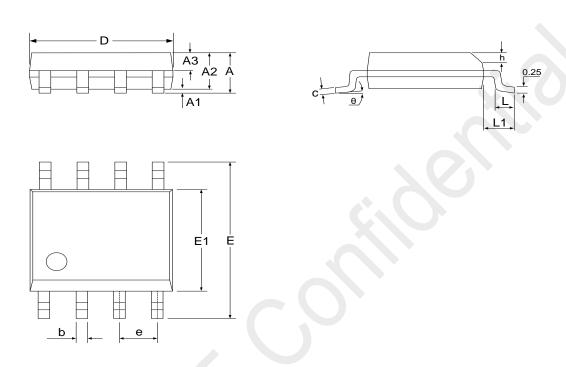


Figure 16. Narrow Body SOIC-8 Packaging

**Table 17.Narrow Body SOIC-8 Packaging Scale** 

Cumbal		Scale (mm)					
Symbol	Min.	Тур.	Max.				
Α	-	-	1.75				
A1	0.10	-	0.225				
A2	1.30	1.40	1.50				
A3	0.60	0.65	0.70				
b	0.39	-	0.48				
С	0.21	-	0.26				
D	4.70	4.90	5.10				
E	5.80	6.00	6.20				
E1	3.70	3.90	4.10				
е		1.27 BSC					
h	0.25	-	0.50				
L	0.50	-	0.80				
L1		1.05 BSC					
θ	0	-	8°				

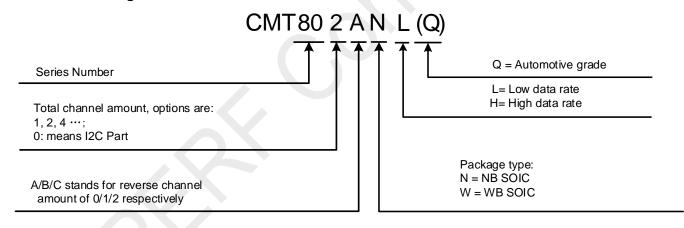
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## 13 Ordering Information

**Table 18. Part Number List** 

Part Number	Min. Order Quantity	Withstand Voltage (rms)	Numbers of Total Channels	Digital Rate (MHz)	Default Output State	Package	MSL
CMT802ANL	3000	3750	2	5	Low	NB SOIC-8	1
CMT802ANH	3000	3750	2	5	High	NB SOIC-8	1
CMT802BNL	3000	3750	2	5	Low	NB SOIC-8	1
CMT802BNH	3000	3750	2	5	High	NB SOIC-8	1
CMT802CNL	3000	3750	2	5	Low	NB SOIC-8	1
CMT802CNH	3000	3750	2	5	High	NB SOIC-8	1

#### **Part Number Naming Rule:**



Please visit <u>www.hoperf.com</u> for more product/product line information.

Please contact <a href="mailto:sales@hoperf.com">sales@hoperf.com</a> or your local sales representative for sales or pricing requirements.

# 14 Tape and Reel Information

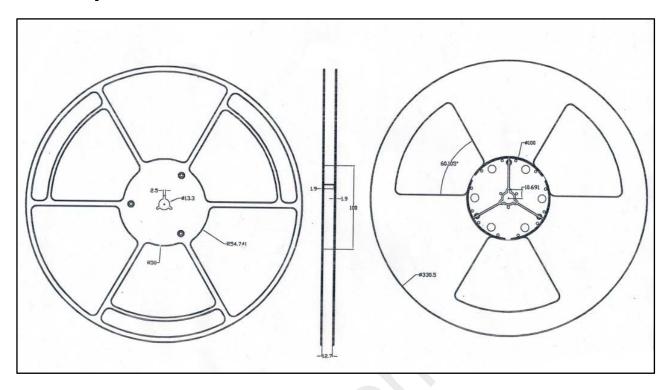


Figure 17. CMT802XNX SOIC-8 Tape & Reel Information

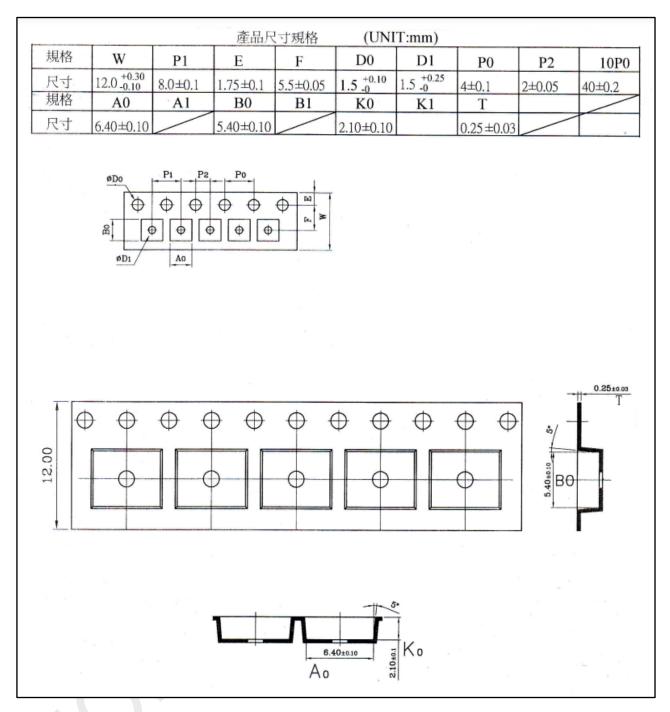


Figure 18. CMT802XNX SOIC-8 Tape & Reel Information

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# 15 Revise History

Table 19. Revise Record

Version No.	Chapter	Description	Date
0.1	All	Initial version	2023/03/23
0.2	All	Delete the silver printing section	0000/04/00
	All	Added the CQC cercificate number	2023/04/20
0.2	All	Modified the data rate of 5 Mbps to 10 Mbps.	2023/11/28
0.3	All	Add MSL level in order information	2024/12/03

### 16 Contacts

Shenzhen Hope Microelectronics Co., Ltd.

Address: 30th floor of 8th Building, C Zone, Vanke Cloud City, Xili Sub-district, Nanshan, Shenzhen, GD, P.R. China

**Tel:** +86-755-82973805 / 4001-189-180

**Fax:** +86-755-82973550

**Post Code:** 518052

Sales: sales@hoperf.com
Website: www.hoperf.com

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